

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Wayne Glenn RENKEN et al.
Title: Integrated Process Condition Sensing Wafer and Data Analysis System
Application No.: 10/718,269 Filing Date: November 19, 2003
Examiner: Jermele M. HOLLINGTON Group Art Unit: 2829
Docket No.: SENS.008US3 Conf. No.: 9982

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

**TRANSMITTAL OF RESPONSE TO FINAL OFFICE ACTION,
AND REQUEST FOR THREE-MONTH EXTENSION OF TIME**

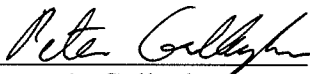
Sir:

Transmitted herewith are the following documents in the above-identified application:

- (1) This Transmittal Letter;
- (2) Response to Final Office Action and Statement of Interview (for which no claims fee is due).
 - ▶ Request is hereby made for a three-month extension of time to file these documents, up to and including **August 8, 2006**.

☒ The extension fee of \$510.00 has been authorized via EFS. Please charge any deficiencies in these fees to Deposit Account No. 502664.

Respectfully submitted,


Peter A. Gallagher
Reg. No. 47,584

August 1, 2006
Date